## Scaling of the Flux Pinning Force in Epitaxial Bi<sub>2</sub>Sr<sub>2</sub>Ca<sub>2</sub>Cu<sub>3</sub>O<sub>x</sub> Thin Films

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(Received 16 November 1992)

Magnetic-field and temperature dependence of the critical current density  $J_c$  is investigated in epitaxial Bi<sub>2</sub>Sr<sub>2</sub>Ca<sub>2</sub>Cu<sub>3</sub>O<sub>x</sub> thin films. For the magnetic field *H* applied parallel to the *c* axis, the flux pinning force density  $F_p$  (= $J_cB$ ) exhibits clear scaling behavior when *H* is normalized by the irreversibility field  $H^*$ . The maximum pinning force density scales linearly with  $H^*$ . This is the first observed scaling of  $F_p$  in high-quality thin films of Bi oxides, which we can reasonably explain with flux-creep theory by assuming that the activation energy is proportional to the flux line spacing.

PACS numbers: 74.60.Ge, 74.60.Jg, 74.72.Hs, 74.76.Bz

Bi oxide cuprate superconductors, Bi<sub>2</sub>Sr<sub>2</sub>CaCu<sub>2</sub>O<sub>x</sub> (Bi-2212) and Bi<sub>2</sub>Sr<sub>2</sub>Ca<sub>2</sub>Cu<sub>3</sub>O<sub>x</sub> (Bi-2223), are technologically important because relatively high transport critical current densities,  $J_c \sim 10^8 - 10^9$  A/m<sup>2</sup>, can be obtained in polycrystalline samples such as Ag-sheathed tapes [1,2].  $J_c$ , however, declines precipitously with magnetic field at moderate temperatures (> 30 K) because of weak flux pinning [1]. The mechanism controlling  $J_c$  in the Bi oxides is one of the key issues for the application of this material. The irreversibility temperatures and the irreversibility fields  $H^*$  above which magnetization becomes reversible and hence  $J_c$  becomes zero are much lower than those observed in YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7</sub> (YBCO) [3].

Recently, we prepared high-quality, epitaxial Bi-2223 thin films by metalorganic chemical vapor deposition, showing high critical temperatures  $T_c$  of 92-97 K [4]. These films have the highest reported  $J_c$  for the Bi-oxide system:  $J_c \ge 10^9$  A/m<sup>2</sup> at 77.3 K in high magnetic fields (1-8 T,  $H \parallel a-b$  plane) [4,5]; zero field  $J_c = 1.3 \times 10^{10}$  $A/m^2$  at 70 K and  $10^{11} A/m^2$  at 30 K [6]. In this Letter we report clear scaling behavior over a wide temperature range, 20-60 K, for the flux pinning force density  $F_p$ , calculated from  $J_c$  values measured in fields parallel to the c axis. Such  $F_p$  scaling has been observed in the transport  $J_c$  of YBCO polycrystalline thin films [7] and epitaxial films [8,9] in limited temperature ranges, but until now was not reported for high-quality Bi-oxide thin films. The  $F_p$  scaling, which is technologically important in predicting the  $J_c$  behavior in magnetic fields, is reasonably explained using flux-creep theory by assuming that the activation energy is proportional to the flux line spacing  $a_0$ 

The details of sample preparation have been reported elsewhere [4]. The 60-80 nm thick films used in this study, deposited on LaAlO<sub>3</sub> (100) single-crystal substrates, were characterized by x-ray diffraction to be single-phase Bi-2223 thin films with the c axis oriented perpendicular to the film surface. High-resolution scanning electron microscopy and reflection high-energy electron diffraction observations confirmed that they were epitaxially grown without apparent grain boundaries.

The transport  $J_c$  was measured by a four-probe dc method for bridge patterns with narrow strip lines, 2 mm

long and 50  $\mu$ m wide, made by a chemical etching technique. Evaporated silver film pads were used as electrodes, which were annealed at 300 °C to reduce the contact resistivity.  $J_c$  is defined by a criterion of 2  $\mu$ V/cm electric field. Magnetic fields were always applied perpendicular to the transport current.

 $J_{c\parallel}(H,T)$  measured in applied fields parallel to the film surface (*a-b* plane) was almost field independent at temperatures  $\lesssim 60$  K [Fig. 1(a)], while  $J_{c\perp}(H,T)$  measured in fields perpendicular to the *a-b* plane decreased sharply with field except at low temperatures ( $\leq 20$  K) [Fig. 1(b)]. Such anisotropic  $J_c$  behavior comes from the quasi-two-dimensional nature of the Bi oxides [6,10,11].

For magnetic fields applied parallel to the *c* direction, the flux pinning force density  $F_p = J_{c\perp}(H,T)B$  was found to scale with the irreversibility field  $H^*$  and the maximum pinning force density  $F_{p_{max}}$ .  $H^*$  was determined to



FIG. 1. Critical current density  $J_c$  measured in a Bi-2223 thin film at various temperatures (a) in magnetic fields applied parallel to the *a*-*b* plane  $J_{c\parallel}(H,T)$  and (b) in fields parallel to the *c* axis  $J_{c\perp}(H,T)$ .

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be the field at which  $J_c$  defined in this particular case by the criterion of 1  $\mu$ V/cm is less than 10<sup>7</sup> A/m<sup>2</sup> [5]. The  $H^*$  values are not dependent on the definition much because of the steep  $J_c$  decline with magnetic field at  $T \ge 30$  K [12]. When the magnetic field was normalized as  $h = H/H^*$ , clear scaling behavior was observed in  $F_p$ (Fig. 2). Similar scaling was also observed in the other two samples with lower  $J_c$ 's over the temperature range 20-60 K. The  $F_{p_{\text{max}}}$  values scale linearly with  $H^*$  for three different Bi-2223 thin film samples as depicted in the inset of Fig. 2. The physical interpretation of these data will be given later. For YBCO a scaling of the form  $F_p = K(H^*)^n \sqrt{h} (1-h)^2$  has been reported for a limited temperature range (71-81 K) [7,9]. However, too large  $H^*$  values at lower temperatures hindered the observation of the exact scaling behavior over a wider temperature range [7,8], and no analysis has been able to explain the  $F_p$  scaling for YBCO satisfactorily.

Figure 3 shows the Arrhenius plots of the resistivity  $\rho(H,T)$  measured in fields parallel to the c axis for the same sample whose  $J_c$  data are shown in Fig. 1.  $T_c(R=0)$  was ~86.5 K. Except near  $1/T_c$  where superconducting fluctuations set in, these plots are almost linear in a wide 1/T range, which indicates that the resistance is caused by a thermally activated process. Temperature independent linear  $\log \rho - 1/T$  plots have been reported for Bi-2212 single crystals [13] and thin films [14]. From the data of Fig. 3 the activation energy  $U_0$ was calculated and plotted against H in the inset of Fig. 3. The  $\rho(H,T)$  data were taken with small  $J = 2.5 \times 10^6$ A/m<sup>2</sup>. Essentially the same  $\rho$ -T curve was also obtained using a smaller current density, which means that the resistivity has been measured in the linear portion of the J-E characteristic. In this experiment, therefore, the calculated  $U_0$  is for the limit  $J \approx 0$ . The inset of Fig. 3 indicates that  $U_0$  is proportional to  $H^{-0.51} \approx 1/\sqrt{H}$ . This  $1/\sqrt{H}$  dependence of  $U_0$  has been demonstrated in the detailed analyses of  $\rho(H,T)$  data in Bi-2212 thin films

[14,15] and has also been observed in Bi-2212 wires [16], although a 1/H dependence has been observed in YBCO [8,17].

The physical origin of the observed  $1/\sqrt{H}$  dependence of  $U_0$  is proposed by Geshkenbein *et al.* [18]. In this model  $U_0$  is associated with the plastic deformation of flux line lattice (FLL) at FLL dislocations, analogous to the thermally activated motion of edge dislocations in crystals.  $U_0$  is estimated as the energy required to create a double kink in the flux line,

$$U_0 = 2\varepsilon_1 a_0 \approx (\Phi_0^2 / 2\pi \mu_0 \lambda^2) \ln \kappa (\Phi_0 / B)^{1/2}$$
  
=  $\mu_0 H_c^2 4\pi \xi^2 \ln \kappa (\Phi_0 / B)^{1/2}$ ,

where  $\varepsilon_1$  is the extra energy per unit length of the flux line along the CuO<sub>2</sub> plane,  $\lambda$  the penetration depth,  $\xi$  the coherence length, and  $\kappa = \lambda/\xi$  [18]. This model is similar to Tinkham's model of thermally activated vortex lattice shear which explains the 1/H dependence for YBCO [19], in that "the motion of a row of fluxons past neighbor rows" [18] occurs. However, in highly anisotropic Bi-oxide system, FLL deforms plastically forming double kinks rather than shearing without kinking [14,18].

We discuss the  $F_p$  scaling observed in our Bi-2223 thin films based on the theory of flux creep [20-22]. In intermediate magnetic-field range,  $H_{c_1} \ll H \ll H_{c_2}$ , collective effects of flux lines are important. The electric field induced by the motion of "flux bundles" is given by E $=Bdv_0\exp(-U_{eff}/kT)$ , where d is a distance which the flux bundles move (of the order of  $a_0$ ),  $v_0$  is an attempt frequency, and  $U_{eff}$  is an effective activation energy. Thermally activated flux motion is assisted by the driving force F=JB, and in the original Anderson-Kim model  $U_{eff}$  is expressed as  $U_{eff}=U_0-JBV_aX_p$ , where  $V_a$  is the activation volume and  $X_p$  is the effective range of the potential well [20]. If  $J_0=U_0/BV_aX$  is defined as the zerotemperature pinning force density when there is no thermal activation and  $j=J/J_0$ ,  $U_{eff}$  can be written as  $U_{eff}=U_0(1-j)$ .



FIG. 2. Scaling of the flux pinning force density  $F_p = J_c B$  measured with the field parallel to the *c* axis. Inset: Relationship between  $F_{p_{max}}$  and  $H^*$  for three different thin film samples.



FIG. 3. Arrhenius plots of the resistivity  $\rho(H,T)$  for the field parallel to the *c* axis. Inset: Activation energy  $U_0$  plotted against applied field *H*.

Until now there have been many reports that suggest that  $U_{\text{eff}}$  is not a linear function of J, but has an upward curvature [17,23-25], which was already pointed out in the classical paper of Beasley, Labusch, and Webb [21]. Recent study on YBCO epitaxial films observed an E-J relation explained by  $U_{\text{eff}} = U_0(1-j)\exp(-j)$  [17]. In our present study we assume a sinusoidal potential U(X) $= \frac{1}{2}U_0\cos(\pi X/X_p) - JBV_aX$  and  $U_{\text{eff}} = U_0(1-j)^{3/2}$  [21, 24], which has a j dependence comparable to  $U_0(1-j)$  $\times \exp(-j)$ . It is to be noted that the functional form of  $U_{\text{eff}}(j)$  does not much affect our analysis: The classical Anderson-Kim model was able to give a result similar to the present study.  $U_{\text{eff}} = U_0(1-j)^{3/2}$  leads to

$$E = Bdv_0 \exp[-U_0(1 - J/J_0)^{3/2}/kT].$$
(1)

In our transport  $J_c$  measurement  $J_c$  was defined by an electric field criterion  $E_c = 2 \mu V/cm$ . By setting  $E = E_c$  and  $J = J_c$  in Eq. (1),

$$J_c = J_0 \{ 1 - [(kT/U_0) \ln(Bdv_0/E_c)]^{2/3} \}.$$
<sup>(2)</sup>

Since  $\ln(Bdv_0/E_c)$  is a slowly varying function of H, we set  $\ln(Bdv_0/E_c) = \ln(E_0/E_c)$  to be a constant [26]. When  $U_0$  is expressed as  $U_0 = \alpha(T)/\sqrt{H}$ , as observed in our  $\rho(H,T)$  data and in Ref. [14], and  $H_0$  is defined as  $(H_0)^{1/2} = \alpha(T)/[kT\ln(E_0/E_c)]$ ,  $F_p = J_c B$  is calculated to be

$$F_p = J_0 B [1 - (H/H_0)^{1/3}].$$
(3)

We next need to calculate  $J_0B = \pi U_0/2V_a X_p$ . Since there have been no experimental results from which  $V_a$ and  $X_p$  can be estimated, we will make the following speculations. If the Lorentz force is exerted effectively on a row of flux lines having number N, the activation volume  $V_a$  can be expressed as  $Na_0\xi_{ab}d_k$ , where  $d_k$  is the length of the flux line along the c axis between the two kinks formed. If we assume that the flux lines are weakly pinned by prevalent pinning centers like point defects, the movable length  $d_k$  can be proportional to kT. The potential well range  $X_p$  is approximated by  $a_0 \approx (\Phi_0/B)^{1/2}$ . Since  $\xi_{ab}$  is weakly temperature dependent for low t $(=T/T_c)$  values,

$$J_0 B \approx \mu_0 K \alpha(T) \sqrt{H} / kT = \mu_0 K \sqrt{H_0} \sqrt{H^*} \sqrt{h} \ln(E_0 / E_c) , \qquad (4)$$

where  $K = \pi [2N\xi_{ab}\Phi_0(d_k/kT)]^{-1}$ . Putting  $H^* = \beta^2 H_0$ , we finally obtain

$$F_p = (\mu_0 K/\beta) H^* \ln(E_0/E_c) \sqrt{h} (1 - \beta^{2/3} h^{1/3}), \qquad (5)$$

which can explain the general feature of the  $F_p$  scaling and the linear  $H^*$ - $F_{p_{max}}$  relationship shown in Fig. 2. The curve fitting to the  $F_p$  data of 30 and 40 K in the range of 0 < h < 0.4 with  $\beta = 1.25$  is shown in Fig. 4. Here, the intersection of the curve with the horizontal axis gives  $H_0$ . We point out that in Eq. (4)  $J_0B$  is a monotonically increasing function of h (and H). This seems to be con-



FIG. 4. Curve fitting by Eqs. (5) and (7) to the  $F_p$  data of 30 and 40 K.

tradictory to the  $F_p$  behavior observed for conventional low- $T_c$  superconductors [27,28]: The field dependence of  $F_p$  can be expressed as  $(H/H_{c2})^p(1-H/H_{c2})^q$ . Since the upper critical fields of Bi oxides are very high compared with  $H^*$ , e.g.,  $\mu_0 H_{c2} \approx 50$  T at 60 K for Bi-2212 single crystals [29], the term  $1 - H/H_{c2}$ , which describes the decrease of the mean superconducting condensation energy with the magnetic field [30], can be neglected in our analysis.

Up to the present stage we have neglected the possibility of flux motion in the opposite direction toward a higher energy barrier by assuming that  $\exp(JBV_aX_p/KT)$  $\gg \exp(-JBV_aX_p/kT)$ . However, this is not the case when the driving force gradient is small compared with kT. The equation which takes into account the probability of flux motion in both directions is [22,24]

$$E = 2E_0 \exp\{-U_0[(1-j)^{3/2} + (\pi/2)j]/kT\}$$
  
× sinh( $\pi U_0 j/2kT$ ). (6)

This equation is applied for large h ( $0 \ll h < 1$ ) where  $j \ll 1$ , and is reduced to  $E = 2E_0 \exp(-U_0/kT) \sinh(\pi U_0 j/2kT)$ , because  $(1-j)^{3/2} + (\pi/2)j \approx 1$ . By following the same procedure used to obtain Eq. (5), we get

$$F_{p} = (2/\pi)\mu_{0}KH^{*}h$$
  
× sinh<sup>-1</sup>( $\frac{1}{2}$  exp{[(1/ $\beta\sqrt{h}$ ) - 1]ln( $E_{0}/E_{c}$ )}). (7)

The curve fitting using Eq. (7) with  $\ln(E_0E_c) = 8$  is also shown in Fig. 4. The experimental  $F_p/F_{p_{max}}$  data agree well with the theoretical result. Equations (5) and (7) have three independent parameters—K,  $\beta$ , and  $\ln(E_0/E_c)$ .  $\beta$  and  $\ln(E_0/E_c)$  were determined to be 1.25 and 8, respectively, by the curve fitting shown in Fig. 4. Then Kwas calculated to be  $3.8 \times 10^8$  A/m<sup>2</sup> from the linear  $F_{p_{max}}$ - $H^*$  relationship shown in the inset of Fig. 2.

The above analysis based on flux-creep theory explains why  $F_p$  scales with  $h = H/H^*$ , not with  $H/H_{c2}$ . Similar treatment was done by Hettinger *et al.* [8] to explain the  $F_p$  scaling observed in YBCO thin films. They overlooked, however, the upward curvature of the U-J relation (inset of Fig. 1 of Ref. [8]), which leads to an underestimation of  $J_0$ , a lower  $J_c$  than observed at 20 K, and an overestimation of  $V_d$ , the volume over which the driving force is determined. If  $V_d$  has the same field dependence as  $V_a$  in Ref. [8], a similar treatment to that used to obtain Eq. (5) in this study leads to  $F_p \sim \sqrt{h}$  (1)  $-\beta h^{2/3}$ ) in low h regime, which better explains their  $F_p$ data. They assumed the individually pinned vortices regime to explain the increase of  $F_p$  in low h regime  $(h \le 0.15)$ . In this regime, however, field independent  $J_c$ is expected and the regime threshold is not necessarily proportional to  $H^*$  [31], which is contradictory to their experimental results and interpretation. Civale et al. assumed a different form  $J_0 \propto 1/[1+B/B_0(T)]$  in their analysis on the magnetization scaling in YBCO single crystals [32].

The major assumption in our analysis is that the  $1/\sqrt{H}$ dependence of  $U_0$  derived from the relation  $U_0 \propto a_0$ , which has been generally observed in Bi-oxide systems for  $\rho$ -T data taken above the irreversibility line (IL), is also the case in the discussion of  $J_c$  below IL. For the highly anisotropic Bi system the theory of Geshkenbein et al. [18] explains the temperature and field dependence of low  $U_0$  values at high temperatures and low current densities. It is reasonable to think that their theory can also be applicable at lower temperatures and high current densities, since 2D-like  $J_c$  behavior was observed also at low temperatures. The stepwise flux penetration with many kinks is expected because the blocking layers between the superconducting CuO<sub>2</sub> layers have a lower superconducting order parameter [10], which is confirmed by the angular dependence of  $J_c(H,\theta)$  determined only by the magnetic field component along the c direction,  $J_c(H,\theta)$  $=J_{c\perp}(H\sin\theta)$  [6,11]. This suggests that the flux motion with formation of double kinks is plausible also below IL. In recent transport measurements in epitaxial YBCO films the 1/B dependence of  $U_0$  is observed both above and below the irreversibility field [17], which gives a justification to our analysis.

The authors would like to thank J. T. Kucera for providing us with the preprint of Ref. [14] before publication. Thanks are also due to M. G. Karkuk and N. A. Fortune for a critical reading and to M. Soltome for technical assistance in sample preparation.

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